TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74HCT74AP,TC74HCT74AF,TC74HCT74AFN

Dual D-Type Flip Flop with Preset and Clear

The TC74HCT74A is a high speed CMOS D FLIP FLOP fabricated with silicon gate C^2MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

This device may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL , NMOS and CMOS output voltage levels.

The signal level applied to the D INPUT is transferred to Q OUTPUT during the positive going transition of the CLOCK pulse.

CLEAR and PRESET are independent of the CLOCK and are accomplished by setting the applopriate input to an "L" level.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

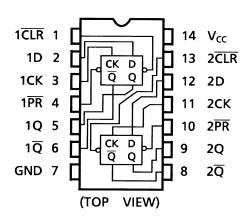
Features

- High speed: $f_{max} = 53 \text{ MHz}$ (typ.) at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 2 \mu A \text{ (max)}$ at $T_a = 25 \text{°C}$
- Compatible with TTL outputs: V_{IH} = 2 V (min)

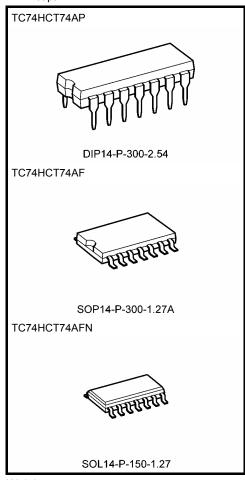
 $V_{IL} = 0.8 \text{ V (max)}$

- Wide interfacing ability: LSTTL, NMOS, CMOS
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: | I_{OH} | = I_{OL} = 4 mA (min)
- Balanced propagation delays: t_{pLH} ≃ t_{pHL}
- Pin and function compatible with 74LS74

Pin Assignment



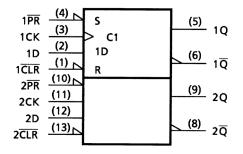
Note: xxxFN (JEDEC SOP) is not available in Japan.



Weight

DIP14-P-300-2.54 : 0.96 g (typ.) SOP14-P-300-1.27A : 0.18 g (typ.) SOL14-P-150-1.27 : 0.12 g (typ.)

IEC Logic Symbol

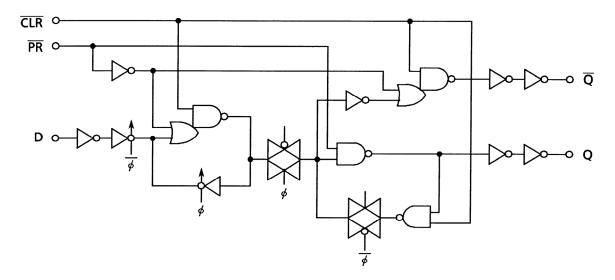


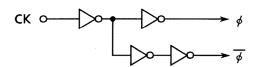
Truth Table

	Inp	uts		Out	puts	Function	
CLR	PR	D	CK	Q	IQ	Tunction	
L	Н	Х	Х	L	Н	Clear	
I	L	Х	Х	Н	L	Preset	
٦	L	Х	Х	Н	Н	_	
Н	Н	L		L	Н		
Н	Н	Н		Н	L		
Н	Н	Х	\Box	Qn	\overline{Q}_{n}	No Change	

X: Don't care

System Diagram







Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7	V
DC input voltage	V _{IN}	-0.5~V _{CC} + 0.5	V
DC output voltage	V _{OUT}	-0.5~V _{CC} + 0.5	V
Input diode current	l _{IK}	±20	mA
Output diode current	lok	±20	mA
DC output current	Гоит	±25	mA
DC V _{CC} /ground current	Icc	±50	mA
Power dissipation	P _D	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T _{stg}	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to $65^{\circ}C$. From Ta = 65 to $85^{\circ}C$ a derating factor of -10 mW/°C shall be applied until 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	4.5~5.5	V
Input voltage	V _{IN}	0~V _{CC}	V
Output voltage	V _{OUT}	0~V _{CC}	V
Operating temperature	T _{opr}	-40~85	°C
Input rise and fall time	t _r , t _f	0~500	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition		-	Га = 25°0		Ta = -4	Unit		
Characteristics				V _{CC} (V)	Min	Тур.	Max	Min	Max	Offic
High-level input voltage	V _{IH}	_		4.5~5.5	2.0	_	_	2.0	_	V
Low-level input voltage	V _{IL}	_		4.5~5.5	_	_	0.8	_	0.8	V
High-level output	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -20 μA	4.5	4.4	4.5	_	4.4	_	V
voltage			$I_{OH} = -4 \text{ mA}$	4.5	4.18	4.31	_	4.13	_	
Low-level output	V _{OL}	V _{IN}	$I_{OL} = 20 \mu A$	4.5	_	0.0	0.1		0.1	V
voltage		= V _{IH} or V _{IL}	I _{OL} = 4 mA	4.5	_	0.17	0.26		0.33	V
Input leakage current	I _{IN}	V _{IN} = V _{CC} or GND		5.5	_	_	±0.1	_	±1.0	μΑ
	I _{CC} V _{IN} = V _{CC}		GND	5.5	_	_	2.0	_	20.0	μΑ
Quiescent supply current	IC	Per input: V _{IN} = 0.5 V o Other input:		5.5	_	_	2.0	_	2.9	mA

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Timing Requirements (input: $t_r = t_f = 6$ ns)

Characteristics	Symbol	Test Condition	Test Condition			Ta = -40 ~85°C	Unit	
			V _{CC} (V)	Тур.	Limit	Limit		
Minimum pulse width	t _{W (L)}		4.5	_	15	19	no	
(CK)	t _{W (H)}	_	5.5	_	14	17	ns	
Minimum pulse width	4		4.5	_	15	19		
(CLR, PR)	t _{W (L)}	_	5.5	_	14	17	ns	
Minimum act un time	t _s		4.5	_	15	19	ns	
Minimum set-up time		_	5.5	_	14	17		
Minimum hold time	t _h		4.5	_	0	0		
Minimum noid time		_	5.5	_	0	0	ns	
Minimum removal time	4		4.5	_	5	5		
(CLR, PR)	t _{rem}	_	5.5	_	5	5	ns	
Clock fraguency	f		4.5	_	27	22	NAL I-	
Clock frequency		_	5.5		30	24	MHz	

AC Characteristics ($C_L = 15 \text{ pF}$, $V_{CC} = 5 \text{ V}$, $Ta = 25^{\circ}\text{C}$, input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Output transition time	t _{TLH} t _{THL}	_	_	6	12	ns
Propagation delay time (CK-Q, \overline{Q})	t _{pLH}	_	_	17	28	ns
Propagation delay time (CLR , PR -Q, Q)	t _{pLH}	_	_	15	25	ns
Maximum clock frequency	f _{max}		29	53	_	MHz

AC Characteristics ($C_L = 50 \text{ pF}$, input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition		-	Га = 25°C		Ta = -4	Unit	
Characteristics	Symbol		V _{CC} (V)	Min	Тур.	Max	Min	Max	Offic
Output transition time	t _{TLH}		4.5	_	8	15	_	19	ns
Output transition time	t _{THL}	<u> </u>	5.5		7	13		16	
Propagation delay time	t _{pLH}		4.5		21	33	_	41	2
$(CK-Q, \overline{Q})$	t_{pHL}	_	5.5	_	19	30	_	37	ns
Propagation delay time	t _{pLH}		4.5	_	18	30	_	38	
$(\overline{CLR}, \overline{PR}-Q, \overline{Q})$	t _{pHL}	_	5.5	_	15	27	_	35	ns
Maximum clock	f		4.5	27	48	_	22	_	MHz
frequency	f _{max}	_	5.5	30	53	_	24	_	IVITZ
Input capacitance	C _{IN}	_			5	10	_	10	pF
Power dissipation capacitance	C _{PD}		(Note)	_	32	_	_	_	pF

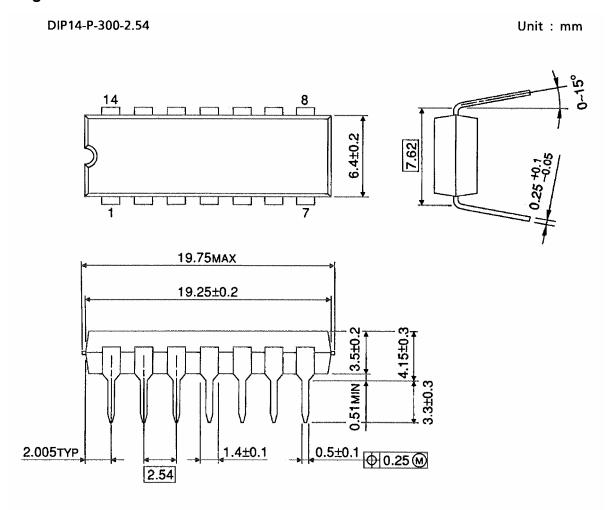
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 I_{CC} (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2$ (per F/F)



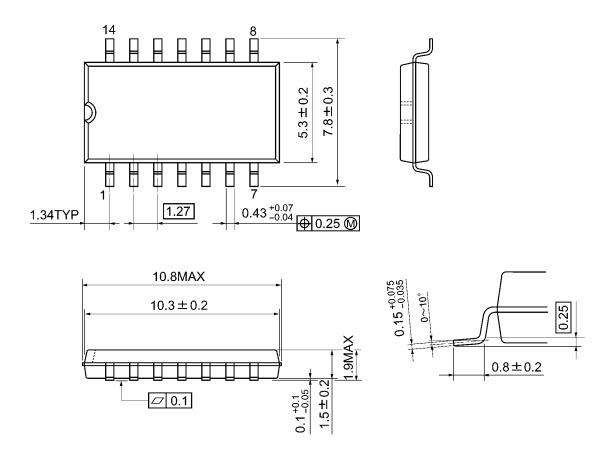
Package Dimensions



Weight: 0.96 g (typ.)

Package Dimensions

SOP14-P-300-1.27A Unit: mm

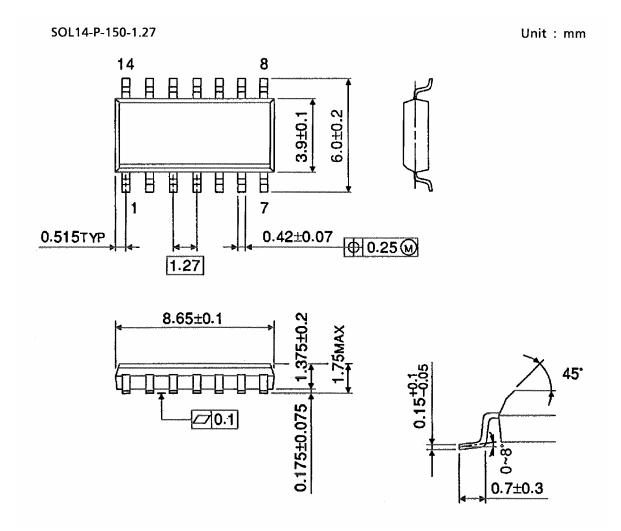


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Weight: 0.18 g (typ.)



Package Dimensions (Note)



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

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20070701-EN GENERAL

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